

Interview Summary	Application No. 10/066,456	Applicant(s) TEIG ET AL.	
	Examiner Binh C. Tat	Art Unit 2825	

All participants (applicant, applicant's representative, PTO personnel):

(1) Binh C. Tat. (3)_____.

(2) Gregory Suh (Reg. No. 48187). (4)_____.

Date of Interview: 13 August 2004.

Type: a) ☐ Telephonic b) ☐ Video Conference
c) ☒ Personal [copy given to: 1) ☐ applicant 2) ☒ applicant's representative]

Exhibit shown or demonstration conducted: d) ☐ Yes e) ☒ No.
If Yes, brief description: _____.

Claim(s) discussed: 1.

Identification of prior art discussed: _____.

Agreement with respect to the claims f) ☒ was reached. g) ☐ was not reached. h) ☐ N/A.

Substance of Interview including description of the general nature of what was agreed to if an agreement was reached, or any other comments: See Continuation Sheet.

(A fuller description, if necessary, and a copy of the amendments which the examiner agreed would render the claims allowable, if available, must be attached. Also, where no copy of the amendments that would render the claims allowable is available, a summary thereof must be attached.)

THE FORMAL WRITTEN REPLY TO THE LAST OFFICE ACTION MUST INCLUDE THE SUBSTANCE OF THE INTERVIEW. (See MPEP Section 713.04). If a reply to the last Office action has already been filed, APPLICANT IS GIVEN ONE MONTH FROM THIS INTERVIEW DATE, OR THE MAILING DATE OF THIS INTERVIEW SUMMARY FORM, WHICHEVER IS LATER, TO FILE A STATEMENT OF THE SUBSTANCE OF THE INTERVIEW. See Summary of Record of Interview requirements on reverse side or on attached sheet.

Examiner Note: You must sign this form unless it is an Attachment to a signed Office action.

Examiner's signature, if required

Continuation of Substance of Interview including description of the general nature of what was agreed to if an agreement was reached, or any other comments: Claims 1, and 15 have been amended as a method for performing technology mapping, the method comprising: a) receiving a IC design layout that is not bounded to a particular technology; b) repeatedly: selecting from the design a candidate sub-network of the IC design layout; identifying at least one replacement sub-network from a storage structure that stores replacement sub-networks that are bound to the particular technology; and replacing the selected candidate sub-network in the design with the replacement sub-network of the IC design layout c) wherein at least a particular one of the selected candidate sub-networks has multiple circuit elements that provide multiple three or more BDD output function of the particular candidate sub-network.